

Search Notes

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Examiner

VAN T. PHAM

Applicant(s)/Patent under
Reexamination

OHYAMA, MINORU

Art Unit

2627

SEARCHED

Class	Subclass	Date	Examiner
369	112.16, 121.	5/26/2006	VP

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East (PGPUB; USPAT; USOCR;EPO;JPO;DERWENT;IBM_T DB) 369, (text search only see search history printout).	5/26/2006	VP
Consulted WayneYoung.	5/26/2006	VP